

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	106666319	WILSON ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
ERIN D CHIEM	2883	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
385	70-72, 89-94	5/21/08	edc

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
wafer same (micro adj lens microlens) and (microlens micro adj lens) same align\$4	12/5/08	edc

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>